

NeoSpectra Module Qualification Tests



P2 Reliability Qualification Tests

Test	Standard	Conditions
Shock	MIL-STD-883 2002	1000g, +/- XYZ, Devices off, 0.5ms Half-Sine, 5x
Vibration	MIL-STD 883 2007	20g, 20-2000Hz, 3 oct/min, +/- XYZ, Devices off
High Temperature Storage Life (HTSL)	JESD22-A-103	85°C, Devices off, 1000 h
Low Temperature Storage Life (LTSL)	JESD22-A 119	-40°C, Devices off, 1000 h
Temperature Humidity Bias (THB)	JESD22-A101	70°C, 85 %RH, Devices on, 500 h
Low Temperature Operating Life (LTOL)	JESD22-A108	-20°C, Device on, 1000 h
Temperature Cycling (TC)	JESD22-A104D	-20°C to +70°C, Devices off, 100 cycle, 3 cph

* Specifications measurements were done for all devices under test at stated operation conditions

**Thank
you**

